

10/580935

Attorney Docket No. 0001.1182

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
APR 20 2005

In re Patent Application of:

Ki-Hyun KIM et al.

Application No.: Not yet assigned

Group Art Unit: Not yet assigned

Ref: PCT/KR2004/003061

Int'l Filing Date: November 25, 2004

Filed: May 30, 2006

Examiner: Not yet assigned

For: INTERLEAVING METHOD FOR LOW DENSITY PARITY CHECK ENCODING

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:
 - 1a. Form PTO-1449.
 - 1b. Copies of IDS citations, except for U.S. Patents and U.S. Patent Application publications.
 - 1c. English language copy of a communication(s) from a foreign Patent Office or a PCT International Search Report.
 - 1d. English language translation (Abstract only) attached to non-English language publications as indicated on the attached Form PTO-1449.
 - 1e. Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.
2. In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is (Check appropriate Items 2a, 2b, 2c and/or 2d)
 - 2a. satisfied for the non-English language publication(s) cited on the enclosed "English language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP § 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, 8th Ed., Rev. 2)

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2b. set forth in the application.

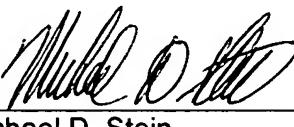
2c. an English language translation (Abstract only) attached to each non-English language publication as indicated on the attached Form PTO-1449.

2d. enclosed as Attachment 1(e), hereto.

3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

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AP20 Rec'd PCT/PTO 30 MAY 2006

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 0001.1182	APPLICATION NO. 10/280935 Not yet assigned
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		FIRST NAMED INVENTOR Ki-Hyun KIM et al.	
		FILING DATE May 30, 2006	GROUP ART UNIT Not yet assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
	AF	EP 1 385 270	1/28/2004	European		
	AG	JP 2004-88449	3/18/2004	Japan		X
	AH	JP 2004-236313	8/19/2004	Japan		X
	AI	WO 2004/021578	3/11/2004	WIPO		X
	AJ					
	AK					

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

			TRANSLATION YES NO
	AL	MacKay, David J.C., "Good Error-Correcting Codes Based on Very Sparse Matrices," <i>IEEE Transactions on Information Theory</i> Vol. 45 No. 2 March 1999, (pp 399-431)	
	AM	PCT International Search Report issued March 31, 2005 re: International Application No. PCT/KR2004/003061	
	AN		

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.